



# Common Ground

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## President's Message

*by Steve Block*

As Summer comes to an end and school get's ready to start, I am amazed how quickly the year is flying by. We have had a very successful year so far in three key measures; attendance is great, we are financially strong, and we have had great technical speakers !

Our next meeting on September 15th promises to be a great topic as well. We have invited a National Level Speaker, Leo G. Henry, to speak about how a finished circuit board can actually be more susceptible to ESD Damage than many of us have been taught all these years ! The idea is that the sensitivity of an IC component increases when attached to a circuit board due to the added capacitance. Leo G will explain this "Charged Board Event" and compare it to the Charged Device Model (CDM) event we are very familiar with. His presentation is called; "Charged Board Events –An ESD Event with more energy/power than CDM". A meeting announcement and a complete Biography of Leo G with more details will be sent in the next few days from Tim Jarrett, our Chapter Program Chairman. Please plan to attend this meeting on Monday September 15th.

Once again I will close by saying THANK YOU to all the volunteers involved in our local chapter on the Board of Directors. Thank you for sharing your valuable time and talents with all of us to strengthen our local chapter and increase our knowledge of ESD events and ESD Control. Your time is very much appreciated !

## 2008 Chapter Meeting Schedule

*Tim Jarrett – Program Chairperson*

### March 10th

- The Chapter's annual Membership Dinner Meeting was held at the Ramada Mall of America, Bloomington, MN
- Technical presentation: Roger Peirce of Simco, "ESD Damage in the Semiconductor and Electronics Manufacturing Industries"

### May 21<sup>st</sup> & 22<sup>nd</sup>

Program Manager Course - Ramada Mall of America, Bloomington, MN

- Seminar: S20.20 Program Development and Assessment with instructors: Ron Gibson of Celestica and John Kinnear of IBM

### June 16<sup>th</sup>

- Meeting Site: Holiday Inn Hotel, Bloomington, MN
- Technical presentation: Draft Standard Test Method, ESD DSTM2.1-2008, Garments - Resistive Characterization, presented by Dave Swenson of Affinity Static Control Consulting, L.L.C

### September 15<sup>th</sup>

- Meeting Site: Ramada Mall of America, Bloomington, MN
- Technical presentation: "Charged Board Events –An ESD Event with more energy/power than CDM", presented by Leo G. Henry

### December 8<sup>th</sup>

- Meeting Site: TBD
- Technical presentation: TBD

Additional meeting details will follow via e-mail announcements. If you are not on the chapter's list, please contact Tim Jarrett [tim.jarrett@bsci.com]

We also strongly encourage all chapter members to consider hosting a future meeting. In addition, if you have a static related control topic you'd like the local board to cover during a future meeting, please contact Tim or any of the Chapter Board members.

## Membership

*by Bernie Reiland*

The membership is at 57 right now. One member must have retired and his mail was returned. We have eight 2007 people that have not renewed for this year. And we are always looking for new members.

## Secretary's Report

### June 9, 2008 Meeting

*by Kevin Leonard*

The meeting was held at the Bloomington Holiday Inn.

4:45 PM: President Steve Block called the meeting to order reviewing the itinerary.

Steve then asked for the following officer reports.

Secretary's Report: Kevin Leonard summarized the minutes from the March meeting which was held at the Ramada Inn located in Bloomington. The guest speaker was Roger Pierce from Simco Corporation. His presentation was titled "ESD Damage In The Electronics and Semiconductor Industries".

Treasurer's Report: Jack Chandler gave the figures from the checking and savings account along with the CD amount. He also reported that we now have a credit card for the group as checks are not always accepted at various venues.

Membership Chair's Report: Bernie Reiland reported current membership total at 58.

National Delegate Report: Dale Parkin recapped the standards meeting which was held in Reno, NV the second week of June. The 30th annual EOS/ESD Symposium will be held at the Westin La Paloma in Tucson, AZ September 7th through the 12th.

Program Chair's Report: Tim Jarrett discussed the chapter's lack of locations to hold future meetings. All suggested locations can be submitted to Steve Block for the September meeting which is tentatively set for the 15th. The potential guest speaker is Leo G. Henry. Under discussion in ESDA standards as a new charge device related ESD event on printed circuit boards called Charge Board Event. The concept is that the sensitivity of the component increases when attached to the PCB due to the added capacitance of the PCB. The ESDA and SMTA may jointly discuss this new charge board event model. The tutorial was a smashing success as 31 attended. Location seemed to be the only thing to review for the next time.

5:10 PM: Steve Block moved to adjourn the business meeting portion.

5:13 PM: Dinner

6:00 PM: Tim Jarrett introduced our guest speaker Dave Swenson from Affinity Static Control Consulting. Dave's presentation was titled "A Review of ESD DSTM 2.1". The standard test method is for evaluating ESD garments. There was a real need to review this document as current sleeve to sleeve method has been around since 1997. There are new requirements such as continuous monitors of garments. The specifications and definitions portion is one of the major changes that are being worked on. The new proposed method would include cuff resistance and measuring all the components of the garment. The tentative release for the reviewable draft version is February or June of 2009.

6:40 PM: Steve Block concludes the meeting.